## Synthesis of low band gap polymers based on bisthiazole and thienylenevinylene for organic thin-film transistors (OTFTs)

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Figure S1. DSC curves of polymers P1-P4.



Figure S2. Surface morphology images of as cast film of polymer P1 (a), P2 (b), P3 (c), and P4 (d) in bottom-gate top-contact configuration.



**Figure S3.** X-ray diffraction spectra of as cast film of polymer P1 (a), P2 (b), P3 (c), and P4 (d) at annealing temperature 150 °C.

## The X-ray crystal structure of 2b

The crystal structure of **2b** (Figure S3) shows the PBTz core to be essential flat, the eleven atoms of the C<sub>6</sub>N<sub>3</sub>S<sub>2</sub> unit being coplanar to within *ca*. 0.02 Å.

*Crystal data for* **2b**: C<sub>40</sub>H<sub>75</sub>N<sub>3</sub>S<sub>2</sub>Si<sub>2</sub>, *M* = 718.33, triclinic, *P*-1 (no. 2), *a* = 7.6455(3), *b* = 11.9092(3), *c* = 25.1027(6) Å, α = 83.133(2), β = 82.326(2), γ = 74.997(3)°, *V* = 2179.31(12) Å<sup>3</sup>, *Z* = 2, *D*<sub>c</sub> = 1.095 g cm<sup>-3</sup>, μ(Mo-Kα) = 0.206 mm<sup>-1</sup>, *T* = 173 K, colourless tabular needles, Oxford Diffraction Xcalibur 3 diffractometer; 14167 independent measured reflections (*R*<sub>int</sub> = 0.0521), *F*<sup>2</sup> refinement,<sup>[X1]</sup> *R*<sub>1</sub>(obs) = 0.0794, *wR*<sub>2</sub>(all) = 0.1774, 9601 independent observed absorption-corrected reflections [|*F*<sub>o</sub>| >  $4\sigma(|F_o|)$ ,  $2\theta_{max} = 66°$ ], 437 parameters. CCDC 1512672.



Figure S3. The crystal structure of 2b. (50% probability ellipsoids).

## **TDDFT Calculations**

Excited State 1: Singlet-A 2.0835 eV 595.09 nm f=8.3884 <S\*\*2>=0.000 422 -> 431 -0.10077 423 -> 430 -0.13602 424 -> 429 -0.19610

425 -> 428	0.29583				
426 -> 427	0.52086				
Excited State	2: Singlet-A	2.2720 eV	545.70 nm	f=0.0001	<s**2>=0.000</s**2>
423 -> 429	0.10726				
424 -> 428	0.16851				
424 -> 430	0.13326				
425 -> 427	0.39337				
425 -> 429	-0.19201				
426 -> 428	0.40857				
Excited State	3: Singlet-A	2.5066 eV	494.64 nm	f=0.7707	<s**2>=0.000</s**2>
423 -> 428	0.13216				
424 -> 427	-0.34248				
424 -> 429	0.10162				
424 -> 431	0.10271				
425 -> 428	-0.31686				
425 -> 430	-0.16635				
426 -> 429	0.36189				

## References

[X1] (a) SHELXTL, Bruker AXS, Madison, WI; (b) SHELX-97, G.M. Sheldrick, Acta Cryst., 2008, A64, 112-122; (c) SHELX-2013, G.M. Sheldrick, Acta Cryst., 2015, C71, 3-8.